# 2SB1416

### Silicon PNP epitaxial planar type

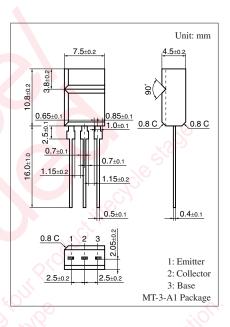
For low-frequency power amplification Complementary to 2SD2136

#### Features

- High forward current transfer ratio h<sub>FE</sub> which has satisfactory linearity
- $\bullet$  Low collector-emitter saturation voltage  $V_{\mbox{CE(sat)}}$
- Allowing automatic insertion with radial taping

#### Absolute Maximum Ratings $T_a = 25^{\circ}C$

Parameter	Symbol	Rating	Unit
Collector-base voltage (Emitter open)	V <sub>CBO</sub>	-60	V
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	-60	v
Emitter-base voltage (Collector open)	V <sub>EBO</sub>	-5	V
Collector current	I <sub>C</sub>	-3	A
Peak collector current	I <sub>CP</sub>	-5	A
Collector power dissipation	P <sub>C</sub>	1.5	W
Junction temperature	Tj	150	°CO
Storage temperature	T <sub>stg</sub>	-55 to +150	°C



#### Electrical Characteristics $T_a = 25^{\circ}C \pm 3^{\circ}C$

Parameter	Symbol	Conditions	Min	Тур	Мах	Unit
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	$I_{\rm C} = -30$ mA, $I_{\rm B} = 0$	-60			V
Base-emitter voltage	V <sub>BE</sub>	$V_{CE} = -4 V, I_C = -3 A$	2.2		-1.8	V
Collector-emitter cutoff current (E-B short)	I <sub>CES</sub>	$V_{CE} = -60 \text{ V}, V_{BE} = 0$			-200	μΑ
Collector-emitter cutoff current (Base open)	I <sub>CEO</sub>	$V_{CE} = -30 \text{ V}, I_B = 0$			-300	μΑ
Emitter-base cutoff current (Collector open)	I <sub>EBO</sub>	$V_{EB} = -5 V, I_C = 0$			-1	mA
Forward current transfer ratio	h <sub>FE1</sub> *	$V_{CE} = -4 V, I_C = -1 A$	40		250	
	h <sub>FE2</sub>	$V_{CE} = -4 V, I_C = -3 A$	10			
Collector-emitter saturation voltage	V <sub>CE(sat)</sub>	$I_{\rm C} = -3$ A, $I_{\rm B} = -0.375$ A			-1.2	V
Transition frequency	f <sub>T</sub>	$V_{CB} = -5 \text{ V}, I_E = 0.1 \text{ A}, f = 200 \text{ MHz}$		270		MHz
Turn-on time	t <sub>on</sub>	$I_{C} = -1 \text{ A}, I_{B1} = -0.1 \text{ A}, I_{B2} = 0.1 \text{ A}$		0.5		μs
Storage time	t <sub>stg</sub>			1.2		μs
Fall time	t <sub>f</sub>			0.3		μs

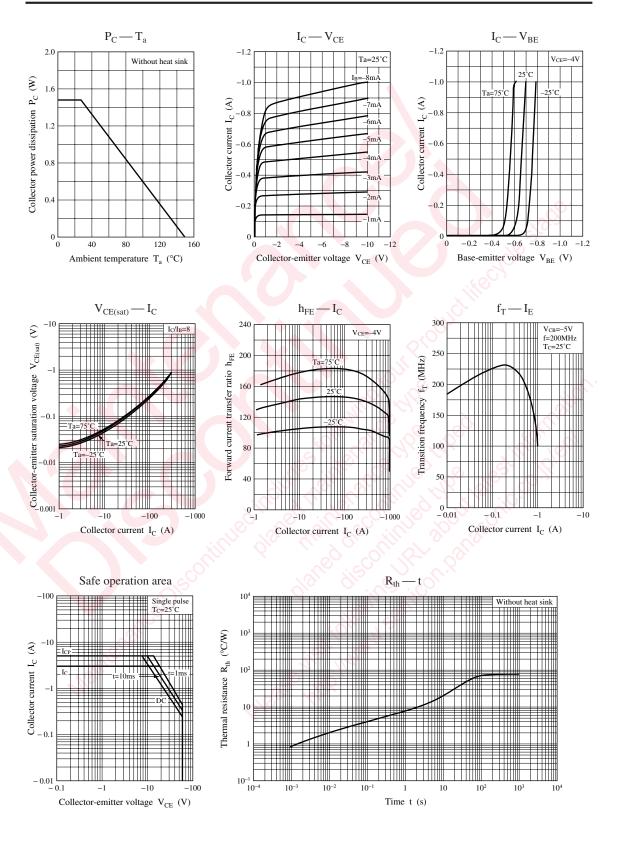
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

2. \*: Rank classification

Rank	Р	Q	R
h <sub>FE1</sub>	40 to 90	70 to 150	120 to 250

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